

08-16-03

IPW

AUG 13 2004



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Banqiu Wu et al.

Serial No. : 10/644,358

Filing Date : August 20, 2003

Title : ENDPOINT DETECTION OF PLASMA-ASSISTED
ETCH PROCESS

Examiner : Stephen D. Rosasco

Group Art Unit : 1756

"Express Mail" mailing label No. EL 996374749US
Date of Deposit: August 13, 2004
I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail" service under 37 CFR 1.10 on the date indicated above and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.
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STATUS INQUIRY

Commissioner for Patents
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Sir:

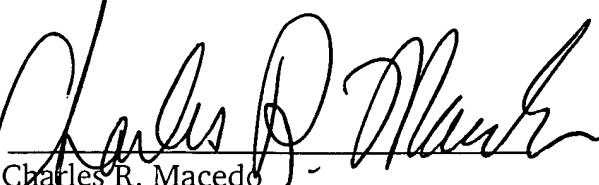
Applicant respectfully inquiries as to the status of the above-identified application.

The Filing Receipt was mailed on September 16, 2003. Applicant's attorney has not received an Examiner's communication from the Patent Office since that date.

Respectfully submitted,

AMSTER, ROTHSTEIN & EBENSTEIN LLP
Attorneys for Applicant
90 Park Avenue
New York, NY 10016
(212) 336-8000

By:


Charles R. Macedo

Registration No. 32,781

Dated: New York, New York
August 13, 2004